

Application/Control No.	Applicant(s)/Patent under Reexamination
09/434,394	YATES ET AL.
Examiner	Art Unit
Hoang-Vu A. Nguyen-Ba	2192

SEARCHED				
Class	Subclass	Date	Examiner	
717	136-140	2/26/2004	HAN	
717	151-161	2/26/2004	HAN	
717	100	2/26/2004	HAN	
703	13-15	2/26/2004	HAN	
703	23,26	2/26/2004	HAN	
712	26,216	2/26/2004	HAN	
712	219,227	2/26/2004	HAN	
712	233-235	2/26/2004	HAN	
712	238-239	2/26/2004	HAN	
714	42,48	2/26/2004	HAN	
714	763-768	2/26/2004	HAN	
Above	Updated	12/23/2004	HAN	
Above	Updated	5/17/2005	HAN	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Inventor Search	2/26/2004	HAN
East Search (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM-TDB) – See Search History Printout	2/26/2004	HAN
East Search (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM-TDB) See Search History Printout	12/23/2004	HAN
East Search (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM-TDB) See Search History Printout	12/1/2005	HAN